

Search Notes

Application/Control No.

10/635,410

Examiner

Tam M. Nguyen

Applicant(s)/Patent under
Reexamination

VAN EGMOND ET AL.

Art Unit

1764

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
interference searched - see PGPUB printout	10/30/2006	tn